

### -30V P-Channel Enhancement Mode MOSFET

#### Description

The AP3407MI uses advanced Trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

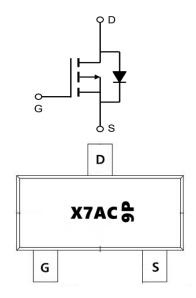
V<sub>DS</sub> = -30V I<sub>D</sub> =-4.8A

 $R_{DS(ON)} < 55m\Omega @ V_{GS}=10V$  (Type: 40mΩ)

#### Application

Battery protection

Load switch Uninterruptible power supply

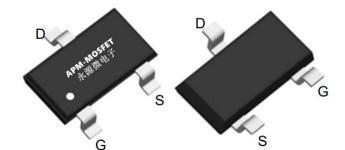


**Top View** 

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**Bottom View** 

04...



#### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS) 3000			
AP3407MI	SOT23-3L	X7AC 9P				
Absolute Maxim	Absolute Maximum Ratings (T <sub>c</sub> =25 <sup>°</sup> Cunless otherwise noted)					
Symbol	Parameter Max.		Units			
VDSS	Drain-Source Voltage	-30	V			
VGSS	Gate-Source Voltage	±20	V			
I⊳@Tc=25℃	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-4.8	A			
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-3.3	A			
IDM	Pulsed Drain Current note1	-20.4	A			
PD	Power Dissipation $T_A = 25^{\circ}C$	2.15	W			
RθJA	Thermal Resistance, Junction to Ambient	104	°C/W			
RθJC	Thermal Resistance from Junction to Ambient <sup>2</sup>	125	°C/W			
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	°C			



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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V(BR)DSS	Drain-Source Breakdown Voltage $V_{GS}$ = 0V, I <sub>D</sub> = -250µA		-30	-	-	V
IDSS	Zero Gate Voltage Drain Current V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V		-	-	-1	μA
IGSS	Gate-Source Leakage	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate-Source Threshold voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250µA	-1	-1.5	-2.5	V
RDS(on)	Ducia Occurre en Otata Decistare e 3	V <sub>GS</sub> = -10V, I <sub>D</sub> = -4.1A	-	40	55	
	Drain-Source on-State Resistance <sup>3</sup>	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3A	-	54	65	mΩ
Ciss	Input Capacitance		-	530	-	pF
Coss	Output Capacitance	$V_{GS} = 0V$ , $V_{DS} = -15V$ , f = 1.0MHz	-	70	-	
Crss	Reverse Transfer Capacitance		-	56	-	
Qg	Total Gate Charge		-	6.8	-	nC
Qgs	Gate-Source Charge	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -4.1A$	-	1.0	-	
Qgd	Gate-Drain Charge	- 104.1A	-	1.4	-	
td(on)	Turn-on Delay Time		-	14	-	
tr	Rise Time	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -15V ,	-	61	-	
td(off)	Turn-off Delay time	R <sub>L</sub> = 15Ω,R <sub>GEN</sub> = 2.5Ω	-	19	-	ns
t <sub>f</sub>	Fall Time		-	10	-	
VSD	Diode Forward Voltage <sup>3</sup>		-	-	-1.2	V
IS	Continuous Source Current	$I_{S} = -4.1A, V_{GS} = 0V$			-4.1	А

#### Electrical Characteristics (TJ=25°C, unless otherwise noted)

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

3. The power dissipation is limited by  $150^{\circ}$ C junction temperature

4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

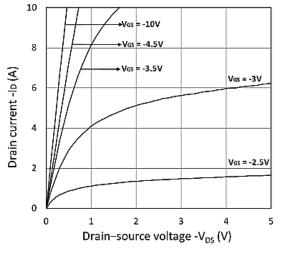
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# AP3407MI

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#### **Typical Characteristics**



**Figure 1. Output Characteristics** 

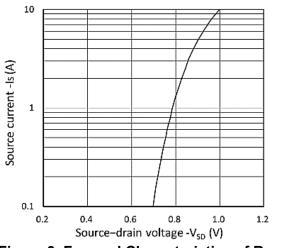


Figure 3. Forward Characteristics of Reverse

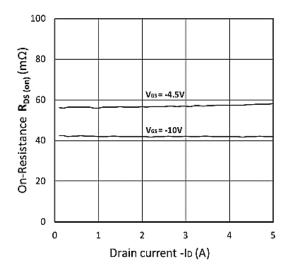
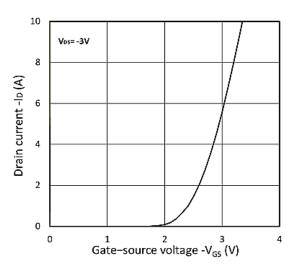
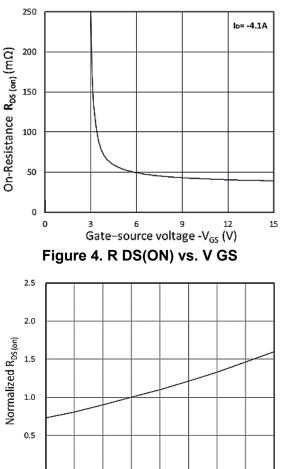


Figure 5. RDS(ON) vs. ID



**Figure 2. Transfer Characteristics** 



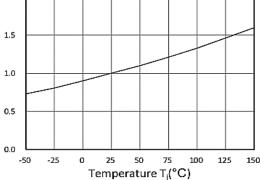


Figure 6. Normalized R DS(on) vs. Temperature



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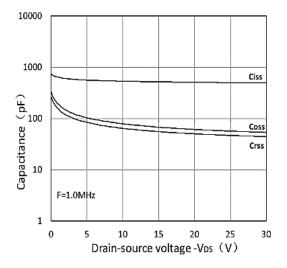
10

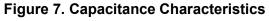
Gate-source voltage -V<sub>GS</sub> (V)

0

0

Vos = -15V Io= -4.1A







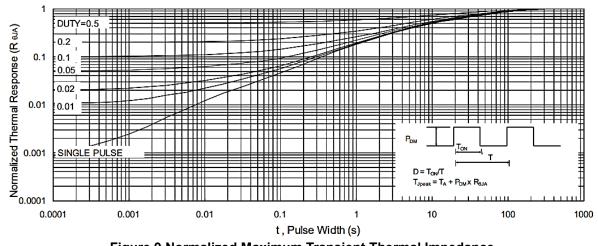
4

Q<sub>g</sub>-Toal Gate Charge (nC)

6

8

2





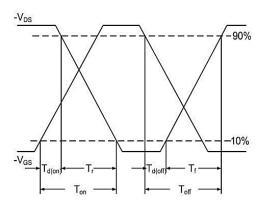


Figure.10 Switching Time Waveform

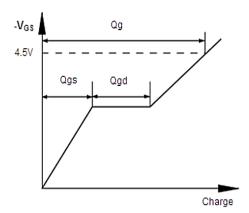
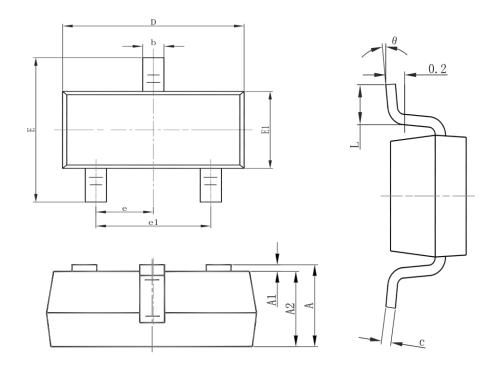


Figure.11 Gate Charge Waveform



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## Package Mechanical Data-SOT23-3-SLS-Single



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
А	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.03	7(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

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Edition	Date	Change
Rve3.9	2018/11/31	Initial release
Rve4.0	2021/12/10	Reduce internal RDS

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AP3407MI RVE1.0

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